

SmartBrowse

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Introduction

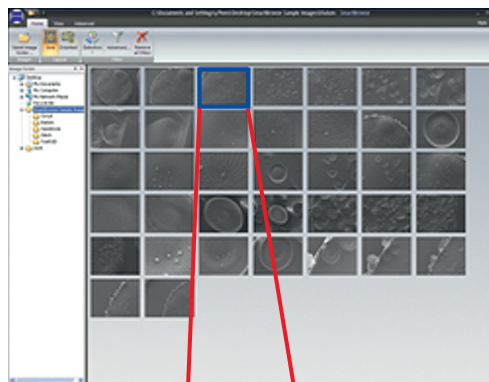
Traditionally navigating through large numbers of images presented a challenge to many scanning electron microscope (SEM) users.

SmartBrowse overcomes this challenge by presenting images spatially referenced by stage coordinates. The result – a clear understanding of the images in context to one another both in terms of space and imaging parameters.

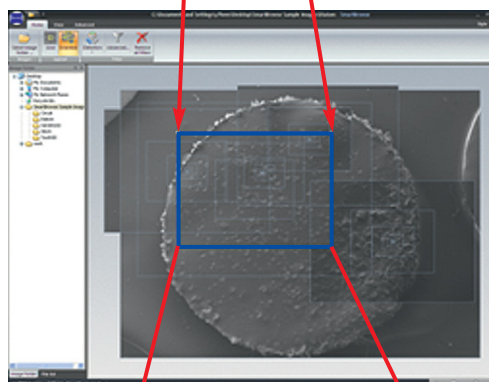
ZEISS SEM users benefit from:

- Enhanced productivity underpinned by intuitive operation
- Deeper insight provided by contextual awareness
- Unlock hidden information with different filtering mechanisms and viewing modes
- Efficient navigation through the images with an Explorer type interface

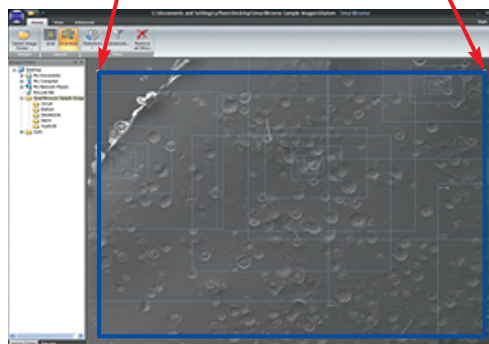
The viewing modes present the most efficient way of browsing the image collection. Grid View displays images in a traditional way and by switching to Oriented View a selected image is shown in relation to the other areas imaged or in relation to the overview image.



Grid View gives a traditional overview of the individual files.



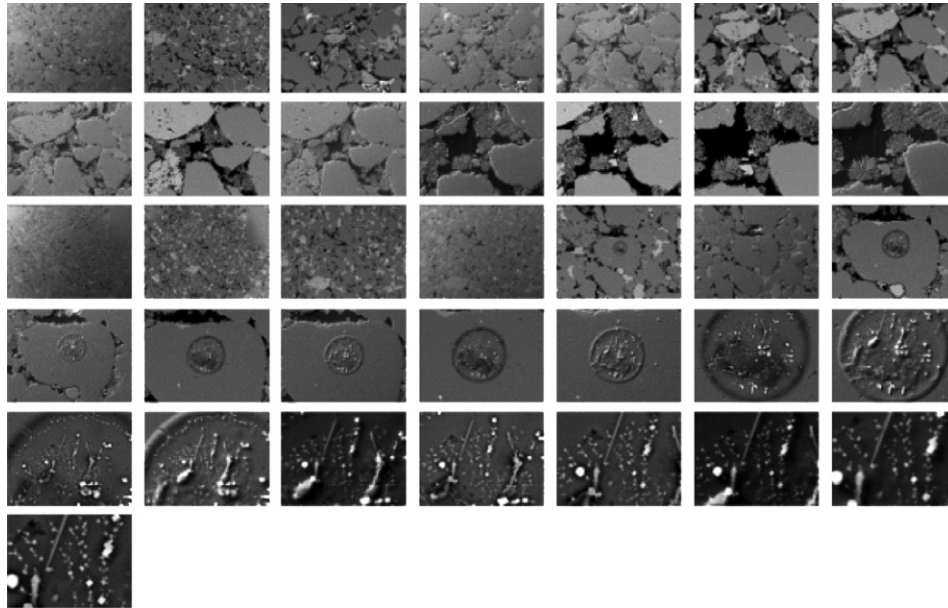
Oriented View provides the spatial context and indicated image locations by grey outlines.



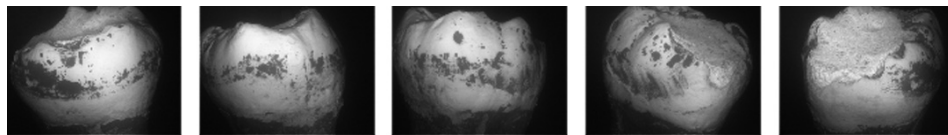
A double click on any image presents the respective choice in full view.

Grid View

Planar image series of a Corrie sandstone thin section.



Series of images of a tooth taken at different tilt angles.



SmartBrowse indicates when additional image information from multiple detector types is available for a selected field. The complementary information produced by multiple detectors in the same field can therefore be brought into use more effectively.

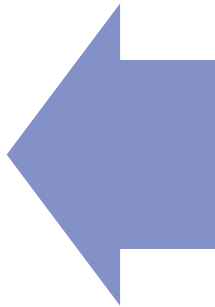
In addition to planar image series, SmartBrowse also elegantly handles tilt series creating the impression of a 3D rotation. This allows for visual interpretation of the images impossible in traditional image viewers.

The user can access the image properties with the complete list of system parameters at the time of imaging or directly launch ZEISS SmartTiff for annotation of the selected image.

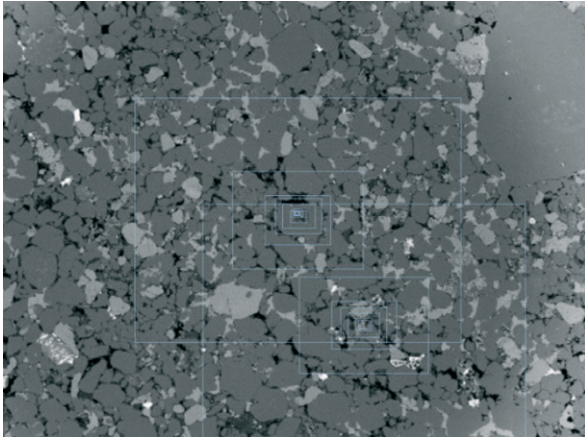
SmartBrowse can be run on the SEM at the same time as collecting data and behaves as a constantly updating image gallery. This provides instant feedback of which data has been acquired and an intuitive way of referencing images taken during a current or previous session. Alternatively SmartBrowse can be installed on a stand-alone PC for off-line retrospective image evaluation. This extends the productivity benefits to offline analysis and frees up the SEM for other work.

SmartBrowse is compatible with all ZEISS scanning electron microscopes and thus provides one-stop image viewing for users of multiple ZEISS SEMs.

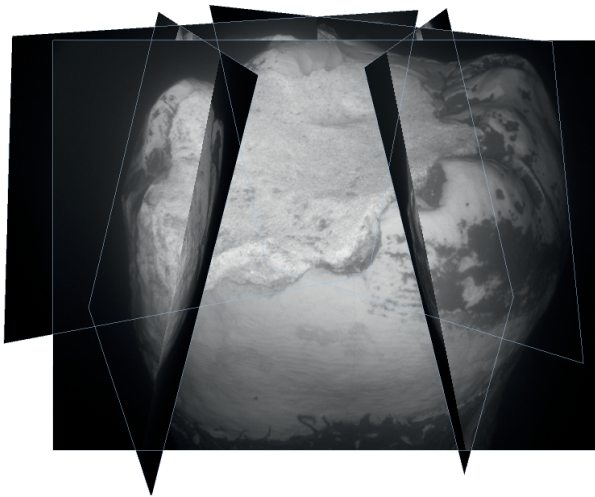
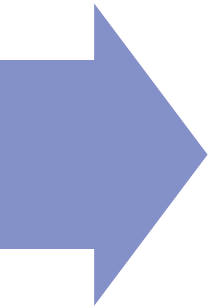
The immediate and intuitive operation of SmartBrowse makes the analysis and viewing of your data not only a pleasure but adds real value to your work.



Oriented View

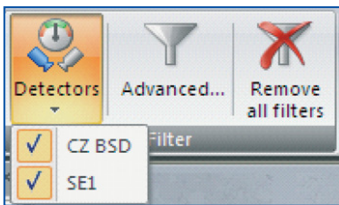


The images are arranged according to the stage coordinates and this instantly visualises where the areas of interest are located with reference to the overall sample.



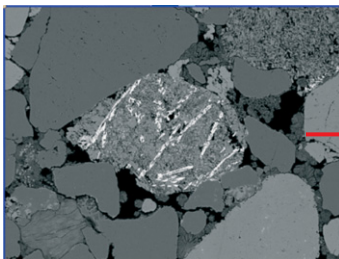
A 3D impression of the specimen is given allowing more efficient interpretation of the image data.

Handling of images from multiple detectors



The entire image set can be filtered by detector type. In case more advanced filtering is required SmartBrowse offers filtering by filename, EHT setting, working distance, probe current and magnification.

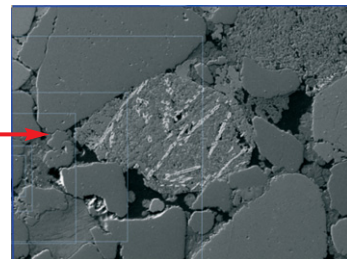
BSD Image ...



Show tabs and choose ...



The SE image of the same field of view.



Pointing the mouse at the top of the screen reveals coloured tabs that show the availability of images taken with other detector types.

Applicability

Compatible with all Carl Zeiss Scanning Electron Microscopes:

EVO® series
 SIGMA™
 SUPRA®
 ULTRA
 MERLIN®

and FIB workstations

AURIGA®
 NEON
 NVision40

System requirements:

Minimum PC requirements:

OS: Windows® XP 32-bit, Vista 32-bit or Windows® 7 32-bit
 CPU: Dual core CPU (Core 2 Duo or better)
 RAM: 2 GB
 HDD: 10 GB free disk space
 GPU: DirectX 10 compliant graphics card with 512 MB of dedicated RAM

Recommended PC requirements:

OS: Windows® 7 32-bit Enterprise, Ultimate or Professional
 CPU: Quad core CPU
 RAM: 3 GB
 HDD: 10 GB free disk space
 GPU: DirectX 11 compliant graphics card with 1 GB of dedicated RAM

Maximum Information – Maximum Insight

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With a broad technology portfolio Carl Zeiss provides instruments both tailored to your requirements and adaptable to your evolving needs. With our highly versatile application solutions we endeavor to be your partner of choice.

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